

PRODUCT/PROCESS CHANGE NOTIFICATION PCN 11255 – Additional information

STM32L4R/S products improvements

MDG - Microcontrollers Division (MCD)

How to order samples?

- For all samples request linked to this PCN, please:
- place a <u>Non-standard</u> sample order (choose Sample Non Std Type from pull down menu)
- insert the PCN number "PCN11255" into the NPO Electronic Sheet/Regional Sheet
- request sample(s) through Notice tool, indicating a single Commercial Product for each request

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RERMCD1603 for PCN11255: Qualification Plan Die 470XXXW (Cut1.4)

Dec 13rd 2018

MDG MCD Quality & Reliability Department



PCN11255: Qualification Plan: Die 470XXXW (Cut 1.4)

- Qualification plan for changes described in the PCN11255
- Reliability report: RERMCD1603

Trial	Test1	Method	Conditions	Sample x lot	
			Conditions	470 Rev W (Cut 1.4)	
DIE	LU	0018695 JESD78	130°C	6 x 1	
	ESD HBM	ANSI/ESDA/ JEDEC JS-001	Ta 25°C 2KV (Class 2)	3 x 1	
	ESD CDM	ANSI/ESDA/ JEDEC JS-002	25°C 250V (class C3)	3 x 1	
	HTOL	MIL-STD-883 Method 1005 JESD22-A108	125°C , 3.6V 168h	77 x 1	

• <u>Note:</u> This plan will be executed with UFBGA169 (DSI option). CDM will be done only in this package and will validate that there is no regression compared to previous cut

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